Search Notes

Applica	ation/Control No.	Applicant(s)/Pate Reexamination	nt under
10/642	2,534	JIN ET AL.	
Exami	ner	Art Unit	
Christo	opher A. Revak	2131	

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SEARCHED						
Class	Subclass	Date	Examiner			
713	200-202	5/18/2005	CR			
709	223-225	5/18/2005	CR			
709	227,228	5/18/2005	CR			
709	238	5/18/2005	CR			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
713	200-202	5/18/2005	CR		
709	223-225	5/18/2005	CR		
709	227,228	5/18/2005	CR		
709/238		5/18/2005	CR		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PGPUB, USOCR	5/18/2005	CR		
PALM Inventor Name Search	5/18/2005	CR		
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	5/18/2005	CR		
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